

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Docket Number (Optional)
WFS.004C

Application Number **10/673,569**
NEW

Applicant(s)
Daniel R. Neal et al.

Filing Date
30 September 2003

Group Art Unit
FBA 1756

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | REF | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|----------------------|-----|-----------------|---------|---------------------|-------|----------|-------------------------------|
| UCAD | A | 3,808,035 | 04-1974 | Stelter, Manfred K. | 427 | 74 | |
| | B | 4,327,129 | 04-1982 | Sepp, Gunther | 427 | 164 | |
| | C | 5,186,975 | 02-1993 | Tizabi et al. | 427 | 99 | |
| | D | 5,460,908 | 10-1996 | Reinberg, Alan R. | 430 | 5 | |
| | E | 5,534,312 | 07-1996 | Hill et al. | 427 | 533 | |
| | F | 5,972,794 | 10-1999 | Katakura, Norihiro | 438 | 704 | |
| | G | 5,691,116 | 11-1997 | Revelli et al. | 430 | 321 | |
| | H | 5,853,960 | 12-1998 | Tran et al. | 430 | 321 | |
| ✓ | I | 5,367,588 | 11-1994 | Hill et al. | 385 | 37 | |
| UCAD | J | 5,814,803 | 09-1998 | Olmstead et al. | 235 | 462.01 | |
| | | | | | | | |

FOREIGN PATENT DOCUMENTS

| REF | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
|--------------|----------------------|----------------------|-------------------|-------|----------|-------------|----|
| | | | | | | YES | NO |
| K | 1,298,724 | 8-13-1987 | Canada | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |
| | | | | | | | |

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

| | |
|----------|---|
| L | Snezhko, L.I., "On the accuracy of the Hartmann method for testing aspherical wavefronts," pp. 505-508, Soviet Journal of Optical Technology, Vol. 47, No. 9, September 1980. |
| | |

EXAMINER **K. Duda**

DATE CONSIDERED **7-20-04**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.